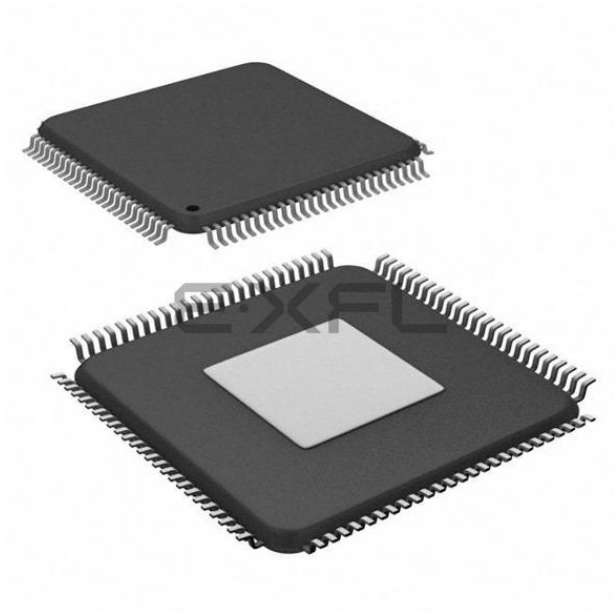
Infineon Technologies - SAK-XE164KM-72F80L AA Datasheet



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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	C166SV2
Core Size	16-Bit
Speed	80MHz
Connectivity	EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	76
Program Memory Size	576KB (576K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	50K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 11x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/sak-xe164km-72f80l-aa

The XE164xM types are offered with several SRAM memory sizes. **Figure 1** shows the allocation rules for PSRAM and DSRAM. Note that the rules differ:

- PSRAM allocation starts from the **lower** address
- DSRAM allocation starts from the **higher** address

For example 8 Kbytes of PSRAM will be allocated at E0’0000h-E0’1FFFh and 8 Kbytes of DSRAM will be at 00’C000h-00’DFFFh.

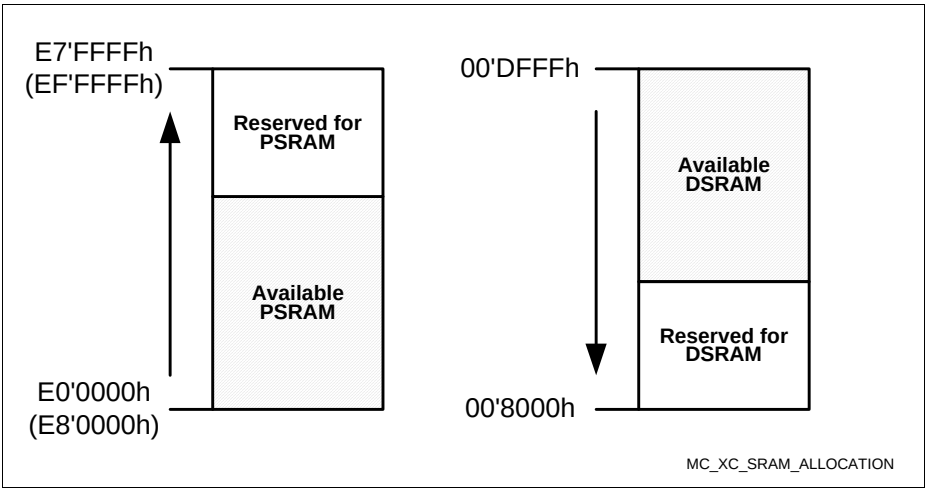

Figure 1 SRAM Allocation

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
33	P5.11	I	In/A	**Bit 11 of Port 5, General Purpose Input**
	ADC0_CH11	I	In/A	**Analog Input Channel 11 for ADC0**
	ADC1_CH11	I	In/A	**Analog Input Channel 11 for ADC1**
34	P5.13	I	In/A	**Bit 13 of Port 5, General Purpose Input**
	ADC0_CH13	I	In/A	**Analog Input Channel 13 for ADC0**
35	P5.15	I	In/A	**Bit 15 of Port 5, General Purpose Input**
	ADC0_CH15	I	In/A	**Analog Input Channel 15 for ADC0**
	RxDC2F	I	In/A	**CAN Node 2 Receive Data Input**
36	P2.12	O0 / I	St/B	**Bit 12 of Port 2, General Purpose Input/Output**
	U0C0_SELO 4	O1	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U0C1_SELO 3	O2	St/B	**USIC0 Channel 1 Select/Control 3 Output**
	TXDC2	O3	St/B	**CAN Node 2 Transmit Data Output**
	READY	IH	St/B	**External Bus Interface READY Input**
37	P2.11	O0 / I	St/B	**Bit 11 of Port 2, General Purpose Input/Output**
	U0C0_SELO 2	O1	St/B	**USIC0 Channel 0 Select/Control 2 Output**
	U0C1_SELO 2	O2	St/B	**USIC0 Channel 1 Select/Control 2 Output**
	$\overline{\text{BHE}}$/$\overline{\text{WRH}}$	OH	St/B	**External Bus Interf. High-Byte Control Output** Can operate either as Byte High Enable ($\overline{\text{BHE}}$) or as Write strobe for High Byte ($\overline{\text{WRH}}$).
39	P2.0	O0 / I	St/B	**Bit 0 of Port 2, General Purpose Input/Output**
	AD13	OH / IH	St/B	**External Bus Interface Address/Data Line 13**
	RxDC0C	I	St/B	**CAN Node 0 Receive Data Input**
	T5INB	I	St/B	**GPT12E Timer T5 Count/Gate Input**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
48	P2.6	O0 / I	St/B	**Bit 6 of Port 2, General Purpose Input/Output**
	U0C0_SELO 0	O1	St/B	**USIC0 Channel 0 Select/Control 0 Output**
	U0C1_SELO 1	O2	St/B	**USIC0 Channel 1 Select/Control 1 Output**
	CC2_CC19	O3 / I	St/B	**CAPCOM2 CC19IO Capture Inp./ Compare Out.**
	A19	OH	St/B	**External Bus Interface Address Line 19**
	U0C0_DX2D	I	St/B	**USIC0 Channel 0 Shift Control Input**
	RxDC0D	I	St/B	**CAN Node 0 Receive Data Input**
	ESR2_6	I	St/B	**ESR2 Trigger Input 6**
49	P4.3	O0 / I	St/B	**Bit 3 of Port 4, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CC2_CC27	O3 / I	St/B	**CAPCOM2 CC27IO Capture Inp./ Compare Out.**
	$\overline{CS3}$	OH	St/B	**External Bus Interface Chip Select 3 Output**
	RxDC2A	I	St/B	**CAN Node 2 Receive Data Input**
	T2EUDA	I	St/B	**GPT12E Timer T2 External Up/Down Control Input**
	CCU62_CCP OS2B	I	St/B	**CCU62 Position Input 2**
53	P0.0	O0 / I	St/B	**Bit 0 of Port 0, General Purpose Input/Output**
	U1C0_DOUT	O1	St/B	**USIC1 Channel 0 Shift Data Output**
	CCU61_CC6 0	O3	St/B	**CCU61 Channel 0 IOutput**
	A0	OH	St/B	**External Bus Interface Address Line 0**
	U1C0_DX0A	I	St/B	**USIC1 Channel 0 Shift Data Input**
	CCU61_CC6 0INA	I	St/B	**CCU61 Channel 0 Input**
	ESR1_11	I	St/B	**ESR1 Trigger Input 11**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
79	P10.8	O0 / I	St/B	**Bit 8 of Port 10, General Purpose Input/Output**
	U0C0_MCLKOUT	O1	St/B	**USIC0 Channel 0 Master Clock Output**
	U0C1_SELO0	O2	St/B	**USIC0 Channel 1 Select/Control 0 Output**
	U2C1_DOUT	O3	St/B	**USIC2 Channel 1 Shift Data Output**
	AD8	OH / IH	St/B	**External Bus Interface Address/Data Line 8**
	CCU60_CCPOS1A	I	St/B	**CCU60 Position Input 1**
	U0C0_DX1C	I	St/B	**USIC0 Channel 0 Shift Clock Input**
	$\overline{\text{BRKIN\_B}}$	I	St/B	**OCDS Break Signal Input**
	T3EUDB	I	St/B	**GPT12E Timer T3 External Up/Down Control Input**
80	P10.9	O0 / I	St/B	**Bit 9 of Port 10, General Purpose Input/Output**
	U0C0_SELO4	O1	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U0C1_MCLKOUT	O2	St/B	**USIC0 Channel 1 Master Clock Output**
	AD9	OH / IH	St/B	**External Bus Interface Address/Data Line 9**
	CCU60_CCPOS2A	I	St/B	**CCU60 Position Input 2**
	TCK_B	IH	St/B	**DAP0/JTAG Clock Input** If JTAG pos. B is selected during start-up, an internal pull-up device will hold this pin high when nothing is driving it. If DAP pos. 1 is selected during start-up, an internal pull-down device will hold this pin low when nothing is driving it.
	T3INB	I	St/B	**GPT12E Timer T3 Count/Gate Input**

Table 5 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
90	P1.4	O0 / I	St/B	**Bit 4 of Port 1, General Purpose Input/Output**
	CCU62_COUT61	O1	St/B	**CCU62 Channel 1 Output**
	U1C1_SELO4	O2	St/B	**USIC1 Channel 1 Select/Control 4 Output**
	U2C0_SELO5	O3	St/B	**USIC2 Channel 0 Select/Control 5 Output**
	A12	OH	St/B	**External Bus Interface Address Line 12**
	U2C0_DX2B	I	St/B	**USIC2 Channel 0 Shift Control Input**
91	P10.15	O0 / I	St/B	**Bit 15 of Port 10, General Purpose Input/Output**
	U1C0_SELO2	O1	St/B	**USIC1 Channel 0 Select/Control 2 Output**
	U0C1_DOUT	O2	St/B	**USIC0 Channel 1 Shift Data Output**
	U1C0_DOUT	O3	St/B	**USIC1 Channel 0 Shift Data Output**
	ALE	OH	St/B	**External Bus Interf. Addr. Latch Enable Output**
	U0C1_DX1C	I	St/B	**USIC0 Channel 1 Shift Clock Input**
92	P1.5	O0 / I	St/B	**Bit 5 of Port 1, General Purpose Input/Output**
	CCU62_COUT60	O1	St/B	**CCU62 Channel 0 Output**
	U1C1_SELO3	O2	St/B	**USIC1 Channel 1 Select/Control 3 Output**
	$\overline{\text{BRKOUT}}$	O3	St/B	**OCDS Break Signal Output**
	A13	OH	St/B	**External Bus Interface Address Line 13**
	U2C0_DX0C	I	St/B	**USIC2 Channel 0 Shift Data Input**

3.3 Central Processing Unit (CPU)

The core of the CPU consists of a 5-stage execution pipeline with a 2-stage instruction-fetch pipeline, a 16-bit arithmetic and logic unit (ALU), a 32-bit/40-bit multiply and accumulate unit (MAC), a register-file providing three register banks, and dedicated SFRs. The ALU features a multiply-and-divide unit, a bit-mask generator, and a barrel shifter.

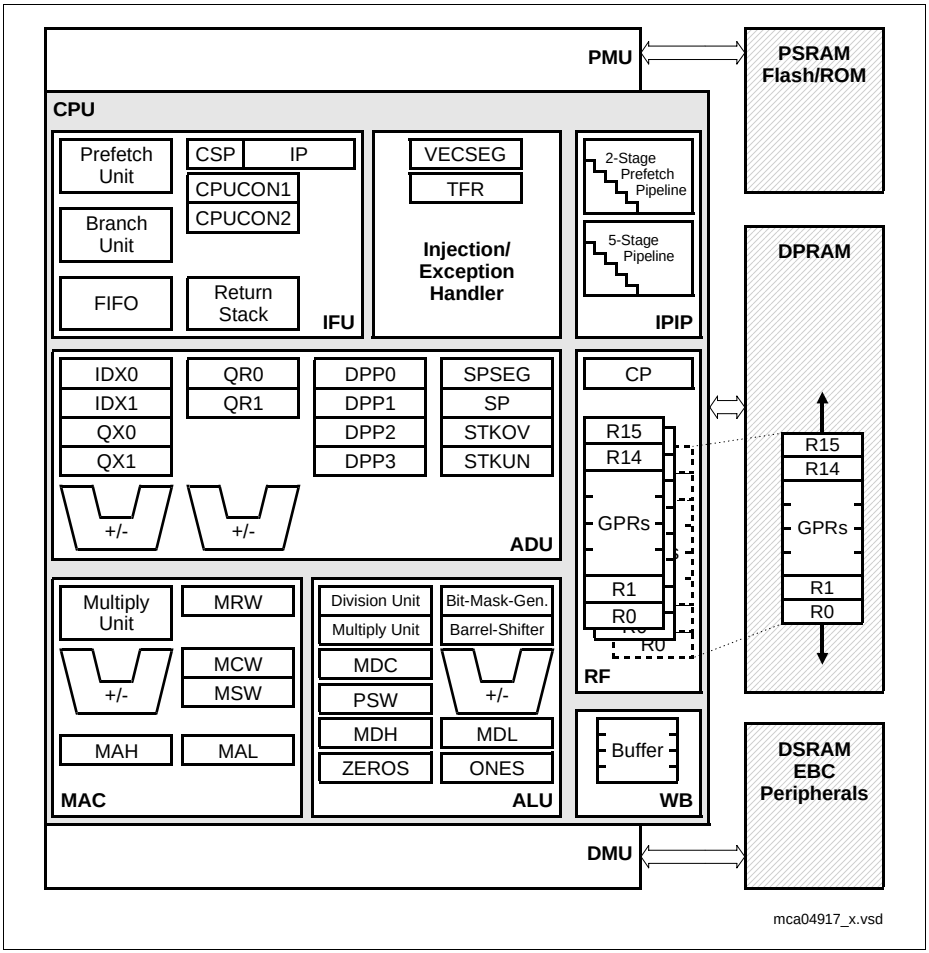

Figure 5 CPU Block Diagram

3.9 Capture/Compare Units CCU6x

The XE164xM types feature the CCU60, CCU61, CCU62 unit(s).

The CCU6 is a high-resolution capture and compare unit with application-specific modes. It provides inputs to start the timers synchronously, an important feature in devices with several CCU6 modules.

The module provides two independent timers (T12, T13), that can be used for PWM generation, especially for AC motor control. Additionally, special control modes for block commutation and multi-phase machines are supported.

Timer 12 Features

- Three capture/compare channels, where each channel can be used either as a capture or as a compare channel.
- Supports generation of a three-phase PWM (six outputs, individual signals for high-side and low-side switches)
- 16-bit resolution, maximum count frequency = peripheral clock
- Dead-time control for each channel to avoid short circuits in the power stage
- Concurrent update of the required T12/13 registers
- Center-aligned and edge-aligned PWM can be generated
- Single-shot mode supported
- Many interrupt request sources
- Hysteresis-like control mode
- Automatic start on a HW event (T12HR, for synchronization purposes)

Timer 13 Features

- One independent compare channel with one output
- 16-bit resolution, maximum count frequency = peripheral clock
- Can be synchronized to T12
- Interrupt generation at period match and compare match
- Single-shot mode supported
- Automatic start on a HW event (T13HR, for synchronization purposes)

Additional Features

- Block commutation for brushless DC drives implemented
- Position detection via Hall sensor pattern
- Automatic rotational speed measurement for block commutation
- Integrated error handling
- Fast emergency stop without CPU load via external signal ($\overline{\text{CTRAP}}$)
- Control modes for multi-channel AC drives
- Output levels can be selected and adapted to the power stage

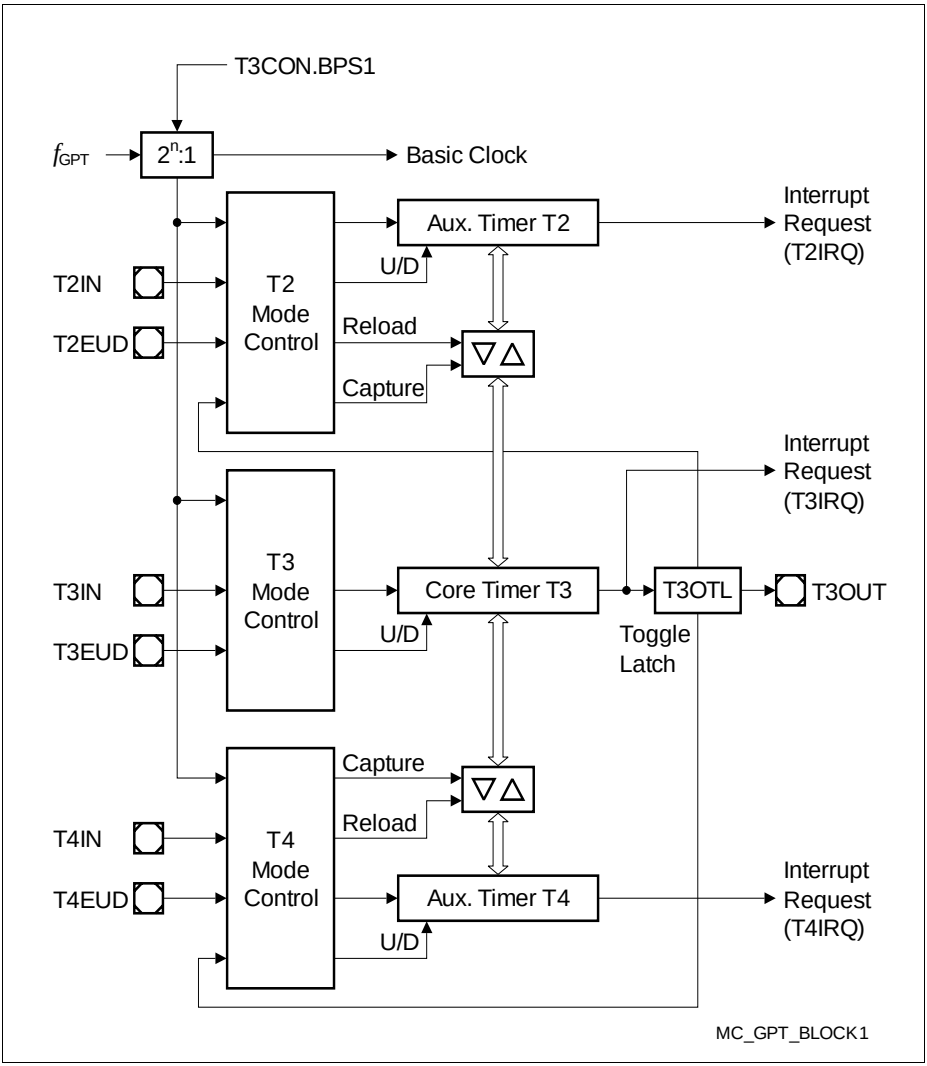

Figure 8 Block Diagram of GPT1

With its maximum resolution of 2 system clock cycles, the **GPT2 module** provides precise event control and time measurement. It includes two timers (T5, T6) and a capture/reload register (CAPREL). Both timers can be clocked with an input clock which is derived from the CPU clock via a programmable prescaler or with external signals. The counting direction (up/down) for each timer can be programmed by software or altered dynamically with an external signal on a port pin (TxEUD[1)]). Concatenation of the timers is supported with the output toggle latch (T6OTL) of timer T6, which changes its state on each timer overflow/underflow.

The state of this latch may be used to clock timer T5, and/or it may be output on pin T6OUT. The overflows/underflows of timer T6 can also be used to clock the CAPCOM2 timers and to initiate a reload from the CAPREL register.

The CAPREL register can capture the contents of timer T5 based on an external signal transition on the corresponding port pin (CAPIN); timer T5 may optionally be cleared after the capture procedure. This allows the XE164xM to measure absolute time differences or to perform pulse multiplication without software overhead.

The capture trigger (timer T5 to CAPREL) can also be generated upon transitions of GPT1 timer T3 inputs T3IN and/or T3EUD. This is especially advantageous when T3 operates in Incremental Interface Mode.

1) Exception: T5EUD is not connected to a pin.

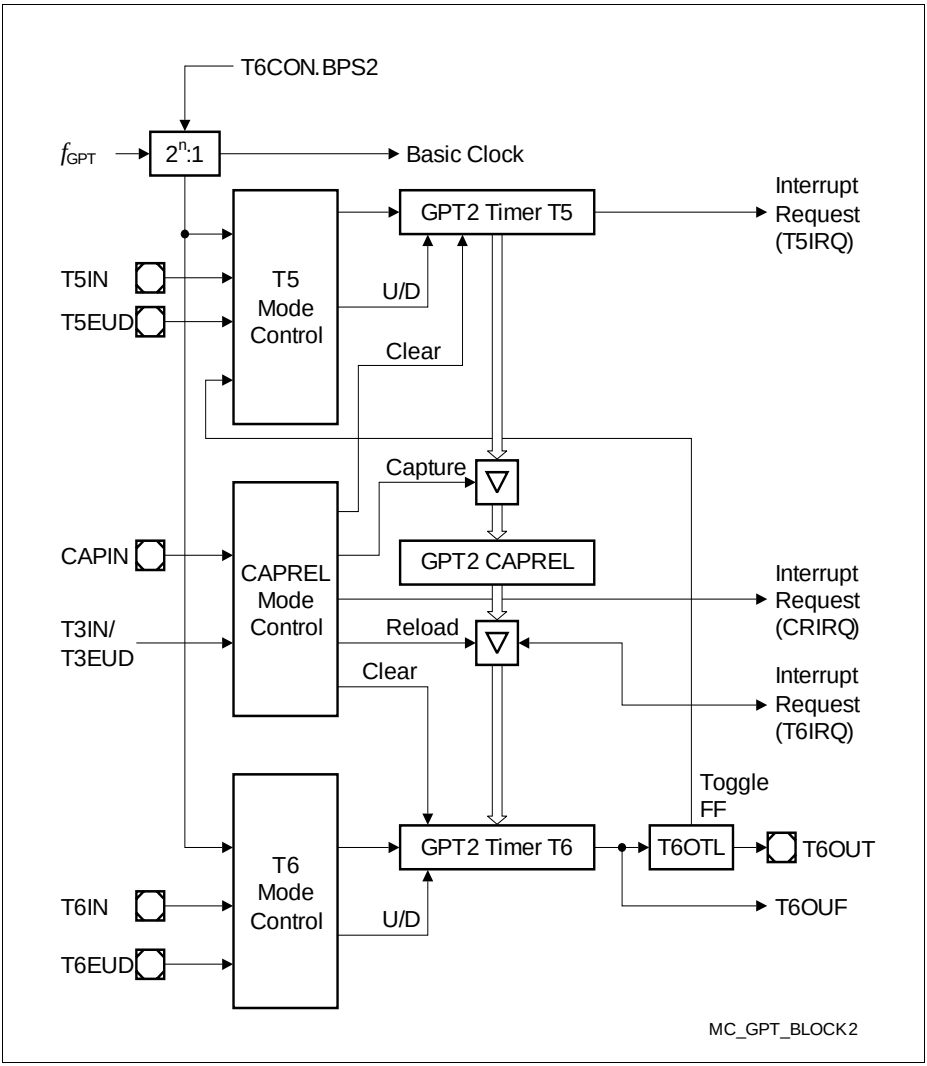

Figure 9 Block Diagram of GPT2

3.14 MultiCAN Module

The MultiCAN module contains independently operating CAN nodes with Full-CAN functionality which are able to exchange Data and Remote Frames using a gateway function. Transmission and reception of CAN frames is handled in accordance with CAN specification V2.0 B (active). Each CAN node can receive and transmit standard frames with 11-bit identifiers as well as extended frames with 29-bit identifiers.

All CAN nodes share a common set of message objects. Each message object can be individually allocated to one of the CAN nodes. Besides serving as a storage container for incoming and outgoing frames, message objects can be combined to build gateways between the CAN nodes or to set up a FIFO buffer.

Note: The number of CAN nodes and message objects depends on the selected device type.

The message objects are organized in double-chained linked lists, where each CAN node has its own list of message objects. A CAN node stores frames only into message objects that are allocated to its own message object list and it transmits only messages belonging to this message object list. A powerful, command-driven list controller performs all message object list operations.

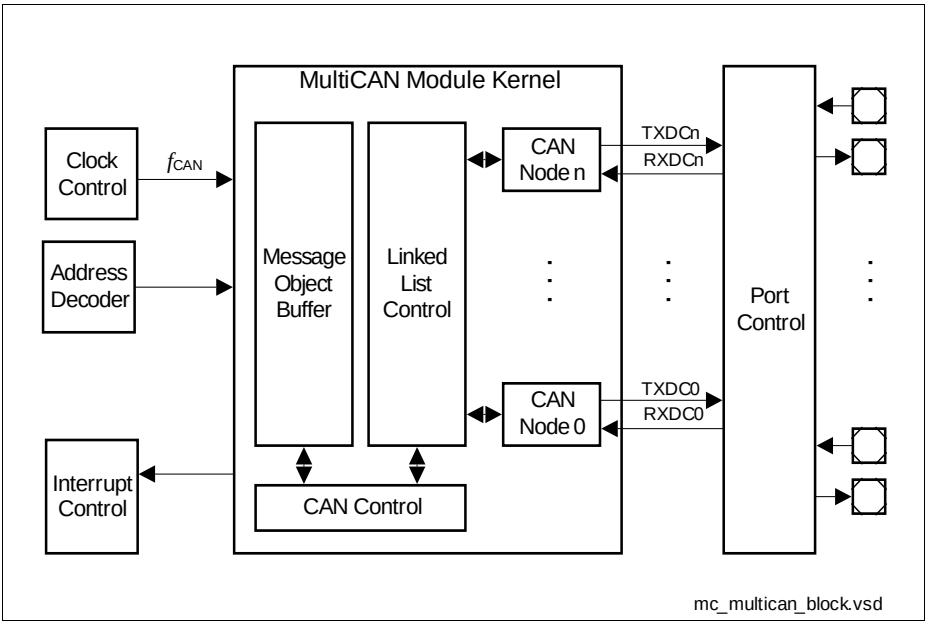

Figure 12 Block Diagram of MultiCAN Module

4 Electrical Parameters

The operating range for the XE164xM is defined by its electrical parameters. For proper operation the specified limits must be respected when integrating the device in its target environment.

4.1 General Parameters

These parameters are valid for all subsequent descriptions, unless otherwise noted.

4.1.1 Absolut Maximum Rating Conditions

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for an extended time may affect device reliability.
During absolute maximum rating overload conditions ($V_{IN} > V_{DDP}$ or $V_{IN} < V_{SS}$) the voltage on V_{DDP} pins with respect to ground (V_{SS}) must not exceed the values defined by the absolute maximum ratings.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Output current on a pin when high value is driven	I_{OH} SR	-30	–	–	mA	
Output current on a pin when low value is driven	I_{OL} SR	–	–	30	mA	
Overload current	I_{OV} SR	-10	–	10	mA	1)
Absolute sum of overload currents	$\Sigma\|I_{OV}\|$ SR	–	–	100	mA	1)
Junction Temperature	T_J SR	-40	–	150	°C	
Storage Temperature	T_{ST} SR	-65	–	150	°C	
Digital supply voltage for IO pads and voltage regulators	V_{DDPA}, V_{DDPB} SR	-0.5	–	6.0	V	
Voltage on any pin with respect to ground (Vss)	V_{IN} SR	-0.5	–	V_{DDP} + 0.5	V	$V_{IN} \le V_{DDP(max)}$

1) Overload condition occurs if the input voltage V_{IN} is out of the absolute maximum rating range. In this case the current must be limited to the listed values by design measures.

Table 12 Operating Conditions (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Absolute sum of overload currents	$\Sigma\|I_{OV}\|$ SR	–	–	50	mA	not subject to production test
Digital core supply voltage for domain M[8)]	V_{DDIM} CC	–	1.5	–		
Digital core supply voltage for domain 1[8)]	V_{DDI1} CC	–	1.5	–		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	4.5	–	5.5	V	
Digital ground voltage	V_{SS} SR	–	0	–	V	

1) To ensure the stability of the voltage regulators the EVRs must be buffered with ceramic capacitors. Separate buffer capacitors with the recomended values shall be connected as close as possible to each V_{DDIM} and V_{DDI1} pin to keep the resistance of the board tracks below 2 Ohm. Connect all V_{DDI1} pins together. The minimum capacitance value is required for proper operation under all conditions (e.g. temperature). Higher values slightly increase the startup time.

2) Use one Capacitor for each pin.

3) This is the reference load. For bigger capacitive loads, use the derating factors listed in the PAD properties section.

4) The timing is valid for pin drivers operating in default current mode (selected after reset). Reducing the output current may lead to increased delays or reduced driving capability (C_L).

5) The operating frequency range may be reduced for specific device types. This is indicated in the device designation (...FxxL). 80 MHz devices are marked ...F80L.

6) Overload conditions occur if the standard operating conditions are exceeded, i.e. the voltage on any pin exceeds the specified range: $V_{OV} > V_{IHmax}$ ($I_{OV} > 0$) or $V_{OV} < V_{ILmin}$ (($I_{OV} < 0$). The absolute sum of input overload currents on all pins may not exceed 50 mA. The supply voltages must remain within the specified limits. Proper operation under overload conditions depends on the application. Overload conditions must not occur on pin XTAL1 (powered by V_{DDIM}).

7) An overload current (I_{OV}) through a pin injects a certain error current (I_{INJ}) into the adjacent pins. This error current adds to the respective pins leakage current (I_{OZ}). The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV}. The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it.The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}| \ K_{OV})$. The additional error current may distort the input voltage on analog inputs.

8) Value is controlled by on-chip regulator

4.2.2 DC Parameters for Lower Voltage Area

Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

Note: Operating Conditions apply.

Table 14 is valid under the following conditions:
$V_{DDP} \geq 3.0$ V; $V_{DDPtyp} = 3.3$ V; $V_{DDP} \leq 4.5$ V

Table 14 DC Characteristics for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Pin capacitance (digital inputs/outputs). To be doubled for double bond pins.[1)]	C_{IO} CC	–	–	10	pF	not subject to production test
Input Hysteresis[2)]	HYS CC	0.07 x V_{DDP}	–	–	V	R_S = 0 Ohm
Absolute input leakage current on pins of analog ports[3)]	$\|I_{OZ1}\|$ CC	–	10	200	nA	$V_{IN} > V_{SS}$; $V_{IN} < V_{DDP}$
Absolute input leakage current for all other pins. To be doubled for double bond pins.[3)1)4)]	$\|I_{OZ2}\|$ CC	–	0.2	2.5	µA	$T_J \leq 110$ °C; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
		–	0.2	8	µA	$T_J \leq 150$ °C; $V_{IN} < V_{DDP}$; $V_{IN} > V_{SS}$
Pull Level Force Current[5)]	$\|I_{PLF}\|$ SR	150	–	–		[6)]
Pull Level Keep Current[7)]	$\|I_{PLK}\|$ SR	–	–	10	µA	[6)]
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 x V_{DDP}	–	V_{DDP} + 0.3	V	
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 x V_{DDP}	V	
Output High voltage[8)]	V_{OH} CC	V_{DDP} - 1.0	–	–	V	$I_{OH} \geq I_{OHmax}$
		V_{DDP} - 0.4	–	–	V	$I_{OH} \geq I_{OHnom}$[9)]

Sample time and conversion time of the XE164xM's A/D converters are programmable. The timing above can be calculated using **Table 18**.
The limit values for f_{ADCI} must not be exceeded when selecting the prescaler value.

Table 18 A/D Converter Computation Table

GLOBCTR.5-0 (DIVA)	A/D Converter Analog Clock f_{ADCI}		INPCRx.7-0 (STC)	Sample Time[1] t_S
000000_B	f_{SYS}		00_H	$t_{ADCI} \times 2$
000001_B	f_{SYS} / 2		01_H	$t_{ADCI} \times 3$
000010_B	f_{SYS} / 3		02_H	$t_{ADCI} \times 4$
:	f_{SYS} / (DIVA+1)		:	$t_{ADCI} \times$ (STC+2)
111110_B	f_{SYS} / 63		FE_H	$t_{ADCI} \times 256$
111111_B	f_{SYS} / 64		FF_H	$t_{ADCI} \times 257$

1) The selected sample time is doubled if broken wire detection is active (due to the presampling phase).

Converter Timing Example A:

Assumptions: f_{SYS} = 80 MHz (i.e. t_{SYS} = 12.5 ns), DIVA = 03_H, STC = 00_H
Analog clock f_{ADCI} = f_{SYS} / 4 = 20 MHz, i.e. t_{ADCI} = 50 ns
Sample time t_S = $t_{ADCI} \times 2$ = 100 ns

Conversion 10-bit:

$t_{C10} = 13 \times t_{ADCI} + 2 \times t_{SYS} = 13 \times 50\text{ ns} + 2 \times 12.5\text{ ns} = 0.675\ \mu s$

Conversion 8-bit:

$t_{C8} = 11 \times t_{ADCI} + 2 \times t_{SYS} = 11 \times 50\text{ ns} + 2 \times 12.5\text{ ns} = 0.575\ \mu s$

Converter Timing Example B:

Assumptions: f_{SYS} = 40 MHz (i.e. t_{SYS} = 25 ns), DIVA = 02_H, STC = 03_H
Analog clock f_{ADCI} = f_{SYS} / 3 = 13.3 MHz, i.e. t_{ADCI} = 75 ns
Sample time t_S = $t_{ADCI} \times 5$ = 375 ns

Conversion 10-bit:

$t_{C10} = 16 \times t_{ADCI} + 2 \times t_{SYS} = 16 \times 75\text{ ns} + 2 \times 25\text{ ns} = 1.25\ \mu s$

Conversion 8-bit:

$t_{C8} = 14 \times t_{ADCI} + 2 \times t_{SYS} = 14 \times 75\text{ ns} + 2 \times 25\text{ ns} = 1.10\ \mu s$

Table 20 Coding of bit fields LEVxV in Register SWDCON0 (cont'd)

Code	Default Voltage Level	Notes[1)]
1001_B	4.5 V	LEV2V: no request
1010_B	4.6 V	
1011_B	4.7 V	
1100_B	4.8 V	
1101_B	4.9 V	
1110_B	5.0 V	
1111_B	5.5 V	

1) The indicated default levels are selected automatically after a power reset.

Table 21 Coding of Bitfields LEVxV in Registers PVCyCONz

Code	Default Voltage Level	Notes[1)]
000_B	0.95 V	
001_B	1.05 V	
010_B	1.15 V	
011_B	1.25 V	
100_B	1.35 V	LEV1V: reset request
101_B	1.45 V	LEV2V: interrupt request[2)]
110_B	1.55 V	
111_B	1.65 V	

1) The indicated default levels are selected automatically after a power reset.

2) Due to variations of the tolerance of both the Embedded Voltage Regulators (EVR) and the PVC levels, this interrupt can be triggered inadvertently, even though the core voltage is within the normal range. It is, therefore, recommended not to use the this warning level.

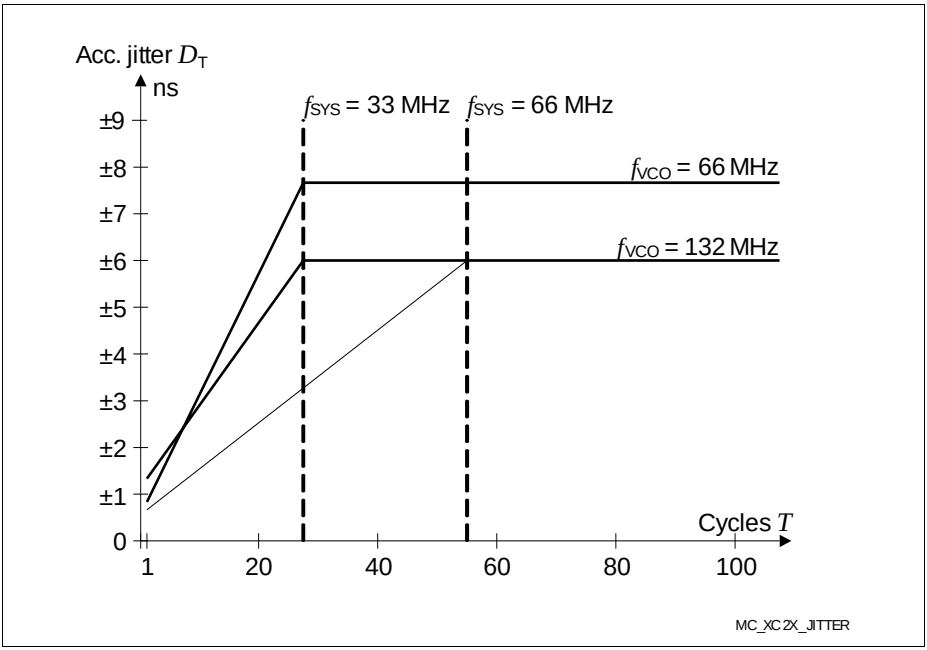

Figure 20 Approximated Accumulated PLL Jitter

Note: The specified PLL jitter values are valid if the capacitive load per pin does not exceed C_L = 20 pF.
The maximum peak-to-peak noise on the pad supply voltage (measured between V_{DDPB} pin 100 and V_{SS} pin 1) is limited to a peak-to-peak voltage of V_{PP} = 50 mV. This can be achieved by appropriate blocking of the supply voltage as close as possible to the supply pins and using PCB supply and ground planes.

4.6.5.1 Bus Cycle Control with the READY Input

The duration of an external bus cycle can be controlled by the external circuit using the READY input signal. The polarity of this input signal can be selected.

Synchronous READY permits the shortest possible bus cycle but requires the input signal to be synchronous to the reference signal CLKOUT.

An asynchronous READY signal puts no timing constraints on the input signal but incurs a minimum of one waitstate due to the additional synchronization stage. The minimum duration of an asynchronous READY signal for safe synchronization is one CLKOUT period plus the input setup time.

An active READY signal can be deactivated in response to the trailing (rising) edge of the corresponding command ($\overline{RD}$ or $\overline{WR}$).

If the next bus cycle is controlled by READY, an active READY signal must be disabled before the first valid sample point in the next bus cycle. This sample point depends on the programmed phases of the next cycle.

Table 32 USIC SSC Master Mode Timing for Lower Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Receive data input setup time to SCLKOUT receive edge	t_4 SR	40	–	–	ns	
Data input DX0 hold time from SCLKOUT receive edge	t_5 SR	-5	–	–	ns	

1) $t_{SYS} = 1 / f_{SYS}$

Table 33 USIC SSC Slave Mode Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge[1)]	t_{10} SR	7	–	–	ns	
Select input DX2 hold after last clock input DX1 receive edge[1)]	t_{11} SR	7	–	–	ns	
Receive data input setup time to shift clock receive edge[1)]	t_{12} SR	7	–	–	ns	
Data input DX0 hold time from clock input DX1 receive edge[1)]	t_{13} SR	5	–	–	ns	
Data output DOUT valid time	t_{14} CC	7	–	33	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

5 Package and Reliability

The XE166 Family devices use the package type PG-LQFP (Plastic Green - Low Profile Quad Flat Package). The following specifications must be regarded to ensure proper integration of the XE164xM in its target environment.

5.1 Packaging

These parameters specify the packaging rather than the silicon.

Table 39 Package Parameters (PG-LQFP-100-8)

Parameter	Symbol	Limit Values		Unit	Notes
		Min.	Max.		
Exposed Pad Dimension	Ex × Ey	–	6.2 × 6.2	mm	–
Power Dissipation	P_{DISS}	–	1.0	W	–
Thermal resistance Junction-Ambient	$R_{\Theta JA}$	–	47	K/W	No thermal via[1)]
			29	K/W	4-layer, no pad[2)]
			23	K/W	4-layer, pad[3)]

1) Device mounted on a 2-layer JEDEC board (according to JESD 51-3) or a 4-layer board without thermal vias; exposed pad not soldered.

2) Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad not soldered.

3) Device mounted on a 4-layer JEDEC board (according to JESD 51-7) with thermal vias; exposed pad soldered to the board.

Note: To improve the EMC behavior, it is recommended to connect the exposed pad to the board ground, independent of the thermal requirements.
Board layout examples are given in an application note.

Package Compatibility Considerations

The XE164xM is a member of the XE166 Family of microcontrollers. It is also compatible to a certain extent with members of similar families or subfamilies.

Each package is optimized for the device it houses. Therefore, there may be slight differences between packages of the same pin-count but for different device types. In particular, the size of the Exposed Pad (if present) may vary.

If different device types are considered or planned for an application, it must be ensured that the board layout fits all packages under consideration.